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Understanding [Embedded - FPGAs \(Field Programmable Gate Array\)](#)

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details

Product Status	Active
Number of LABs/CLBs	-
Number of Logic Elements/Cells	-
Total RAM Bits	-
Number of I/O	69
Number of Gates	6000
Voltage - Supply	3V ~ 3.6V, 4.75V ~ 5.25V
Mounting Type	Surface Mount
Operating Temperature	0°C ~ 70°C (TA)
Package / Case	80-TQFP
Supplier Device Package	80-VQFP (14x14)
Purchase URL	https://www.e-xfl.com/product-detail/microchip-technology/a40mx04-1vqg80

- The Transient Current, page 13 is new (SAR 36930).
- Package names were revised according to standards established in *Package Mechanical Drawings* (SAR 34774)

1.7 Revision 9.0

The following is a summary of the changes in revision 9.0 of this document

- In Table 20, page 23, the limits in VI were changed from -0.5 to VCCI + 0.5 to -0.5 to VCCA + 0.5
- In Table 22, page 25, V_{OH} was changed from 3.7 to 2.4 for the min in industrial and military. V_{IH} had V_{CCI} and that was changed to VCCA

1.8 Revision 6.0

The following is a summary of the changes in revision 6.0 of this document.

- The Ease of Integration, page 1 was updated
- The Temperature Grade Offerings, page 5 is new
- The Speed Grade Offerings, page 5 is new
- The General Description, page 6 was updated
- The MultiPlex I/O Modules, page 11 was updated
- The User Security, page 12 was updated
- Table 6, page 13 was updated
- The Power Dissipation, page 14 was updated.
- The Static Power Component, page 14 was updated
- The Equivalent Capacitance, page 15 was updated
- Figure 13, page 17 was updated
- Table 10, page 18 was updated.
- Figure 14, page 18 was updated.
- Table 11, page 19 was updated.

2 40MX and 42MX FPGA Families

2.1 Features

The following sections list out various features of the 40MX and 42MX FPGA family devices.

2.1.1 High Capacity

- Single-Chip ASIC Alternative
- 3,000 to 54,000 System Gates
- Up to 2.5 kbits Configurable Dual-Port SRAM
- Fast Wide-Decode Circuitry
- Up to 202 User-Programmable I/O Pins

2.1.2 High Performance

- 5.6 ns Clock-to-Out
- 250 MHz Performance
- 5 ns Dual-Port SRAM Access
- 100 MHz FIFOs
- 7.5 ns 35-Bit Address Decode

2.1.3 HiRel Features

- Commercial, Industrial, Automotive, and Military Temperature Plastic Packages
- Commercial, Military Temperature, and MIL-STD-883 Ceramic Packages
- QML Certification
- Ceramic Devices Available to DSCC SMD

2.1.4 Ease of Integration

- Mixed-Voltage Operation (5.0 V or 3.3 V for core and I/Os), with PCI-Compliant I/Os
- Up to 100% Resource Utilization and 100% Pin Locking
- Deterministic, User-Controllable Timing
- Unique In-System Diagnostic and Verification Capability with Silicon Explorer II
- Low Power Consumption
- IEEE Standard 1149.1 (JTAG) Boundary Scan Testing

2.2 Product Profile

The following table gives the features of the products.

Table 1 • Product profile

Device	A40MX02	A40MX04	A42MX09	A42MX16	A42MX24	A42MX36
Capacity						
System Gates	3,000	6,000	14,000	24,000	36,000	54,000
SRAM Bits	–	–	–	–	–	2,560
Logic Modules						
Sequential	–	–	348	624	954	1,230
Combinatorial	295	547	336	608	912	1,184
Decode	–	–	–	–	24	24
Clock-to-Out	9.5 ns	9.5 ns	5.6 ns	6.1 ns	6.1 ns	6.3 ns
SRAM Modules (64x4 or 32x8)						
	–	–	–	–	–	10
Dedicated Flip-Flops	–	–	348	624	954	1,230

3 40MX and 42MX FPGAs

3.1 General Description

Microsemi's 40MX and 42MX families offer a cost-effective design solution at 5V. The MX devices are single-chip solutions and provide high performance while shortening the system design and development cycle. MX devices can integrate and consolidate logic implemented in multiple PALs, CPLDs, and FPGAs. Example applications include high-speed controllers and address decoding, peripheral bus interfaces, DSP, and co-processor functions.

The MX device architecture is based on Microsemi's patented antifuse technology implemented in a 0.45µm triple-metal CMOS process. With capacities ranging from 3,000 to 54,000 system gates, the MX devices provide performance up to 250 MHz, are live on power-up and have one-fifth the standby power consumption of comparable FPGAs. MX FPGAs provide up to 202 user I/Os and are available in a wide variety of packages and speed grades.

A42MX24 and A42MX36 devices also feature multiPlex I/Os, which support mixed-voltage systems, enable programmable PCI, deliver high-performance operation at both 5.0V and 3.3V, and provide a low-power mode. The devices are fully compliant with the PCI local bus specification (version 2.1). They deliver 200 MHz on-chip operation and 6.1 ns clock-to-output performance.

The 42MX24 and 42MX36 devices include system-level features such as IEEE Standard 1149.1 (JTAG) Boundary Scan Testing and fast wide-decode modules. In addition, the A42MX36 device offers dual-port SRAM for implementing fast FIFOs, LIFOs, and temporary data storage. The storage elements can efficiently address applications requiring wide data path manipulation and can perform transformation functions such as those required for telecommunications, networking, and DSP.

All MX devices are fully tested over automotive and military temperature ranges. In addition, the largest member of the family, the A42MX36, is available in both CQ208 and CQ256 ceramic packages screened to MIL-STD-883 levels. For easy prototyping and conversion from plastic to ceramic, the CQ208 and PQ208 devices are pin-compatible.

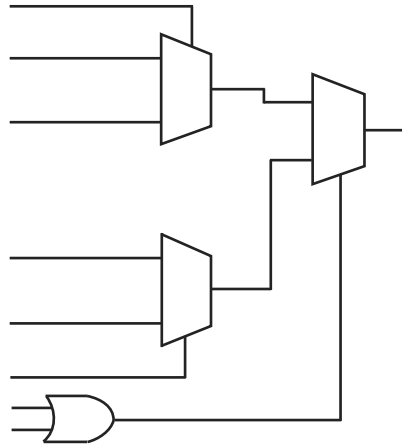
3.2 MX Architectural Overview

The MX devices are composed of fine-grained building blocks that enable fast, efficient logic designs. All devices within these families are composed of logic modules, I/O modules, routing resources and clock networks, which are the building blocks for fast logic designs. In addition, the A42MX36 device contains embedded dual-port SRAM modules, which are optimized for high-speed data path functions such as FIFOs, LIFOs and scratch pad memory. A42MX24 and A42MX36 also contain wide-decode modules.

3.2.1 Logic Modules

The 40MX logic module is an eight-input, one-output logic circuit designed to implement a wide range of logic functions with efficient use of interconnect routing resources.(see the following figure).

The logic module can implement the four basic logic functions (NAND, AND, OR and NOR) in gates of two, three, or four inputs. The logic module can also implement a variety of D-latches, exclusivity functions, AND-ORs and OR-ANDs. No dedicated hard-wired latches or flip-flops are required in the array; latches and flip-flops can be constructed from logic modules whenever required in the application.

Figure 2 • 42MX C-Module Implementation

The 42MX devices contain three types of logic modules: combinatorial (C-modules), sequential (S-modules) and decode (D-modules). The following figure illustrates the combinatorial logic module. The S-module, shown in Figure 4, page 8, implements the same combinatorial logic function as the C-module while adding a sequential element. The sequential element can be configured as either a D-flip-flop or a transparent latch. The S-module register can be bypassed so that it implements purely combinatorial logic.

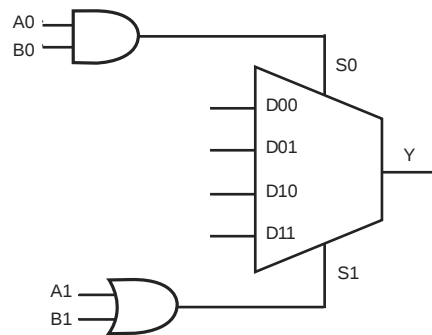
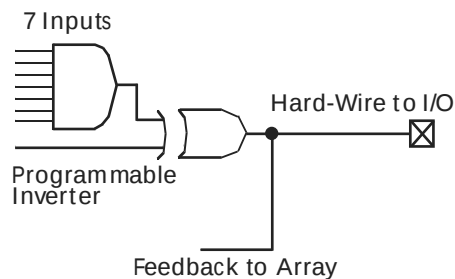
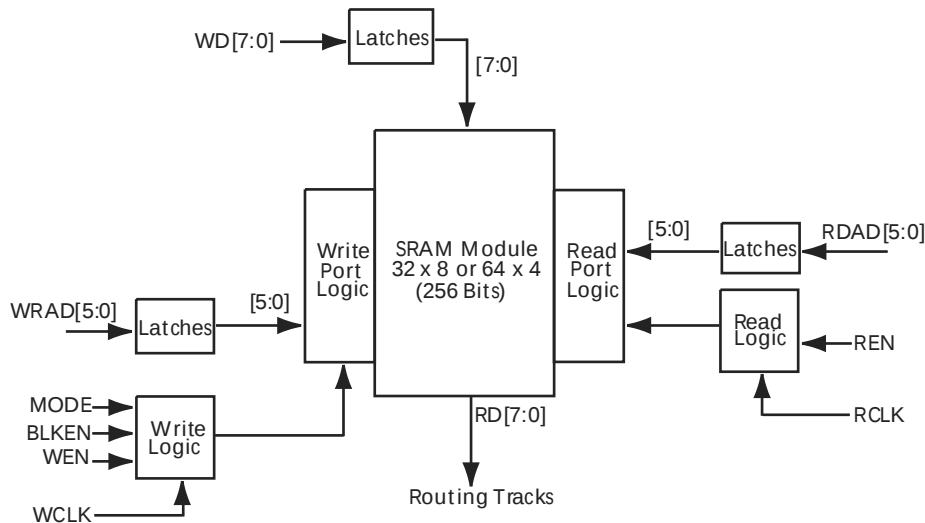
Figure 3 • 42MX C-Module Implementation

Figure 5 • A42MX24 and A42MX36 D-Module Implementation**Figure 6 • A42MX36 Dual-Port SRAM Block**

3.2.3 Routing Structure

The MX architecture uses vertical and horizontal routing tracks to interconnect the various logic and I/O modules. These routing tracks are metal interconnects that may be continuous or split into segments. Varying segment lengths allow the interconnect of over 90% of design tracks to occur with only two antifuse connections. Segments can be joined together at the ends using antifuses to increase their lengths up to the full length of the track. All interconnects can be accomplished with a maximum of four antifuses.

3.2.3.1 Horizontal Routing

Horizontal routing tracks span the whole row length or are divided into multiple segments and are located in between the rows of modules. Any segment that spans more than one-third of the row length is considered a long horizontal segment. A typical channel is shown in Figure 7, page 10. Within horizontal routing, dedicated routing tracks are used for global clock networks and for power and ground tie-off tracks. Non-dedicated tracks are used for signal nets.

3.2.3.2 Vertical Routing

Another set of routing tracks run vertically through the module. There are three types of vertical tracks: input, output, and long. Long tracks span the column length of the module, and can be divided into multiple segments. Each segment in an input track is dedicated to the input of a particular module; each segment in an output track is dedicated to the output of a particular module. Long segments are uncommitted and can be assigned during routing.

Each output segment spans four channels (two above and two below), except near the top and bottom of the array, where edge effects occur. Long vertical tracks contain either one or two segments. An example of vertical routing tracks and segments is shown in Figure 7, page 10.

Each I/O cell has three boundary-scan register cells, each with a serial-in, serial-out, parallel-in, and parallel-out pin. The serial pins are used to serially connect all the boundary-scan register cells in a device into a boundary-scan register chain, which starts at the TDI pin and ends at the TDO pin. The parallel ports are connected to the internal core logic tile and the input, output and control ports of an I/O buffer to capture and load data into the register to control or observe the logic state of each I/O.

Figure 14 • 42MX IEEE 1149.1 Boundary Scan Circuitry

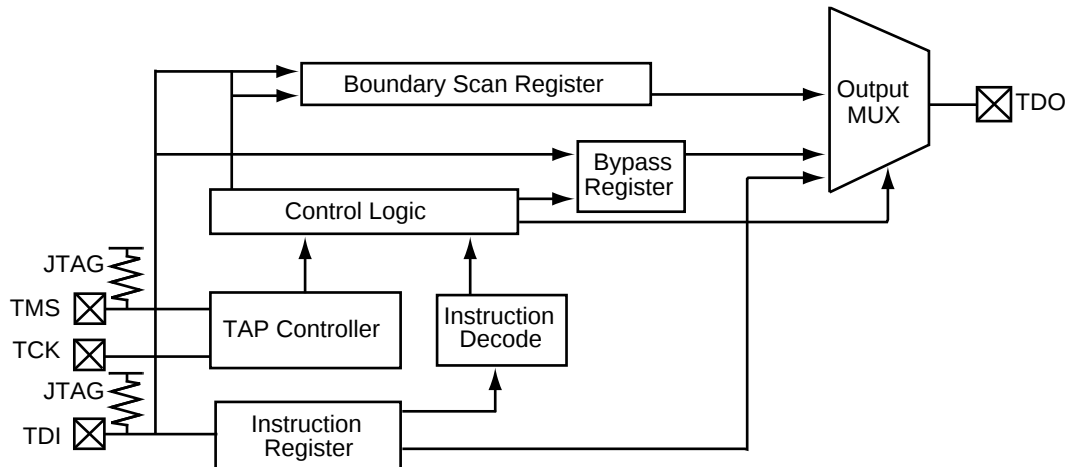
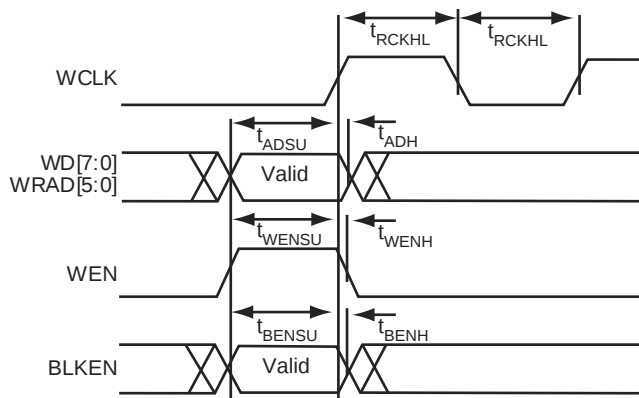


Table 9 • Test Access Port Descriptions

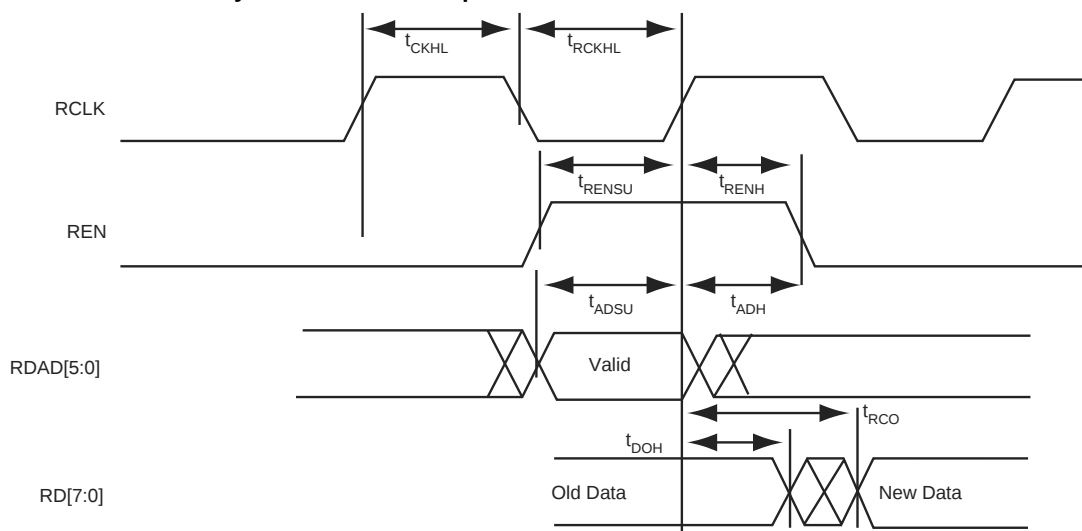
Port	Description
TMS (Test Mode Select)	Serial input for the test logic control bits. Data is captured on the rising edge of the test logic clock (TCK).
TCK (Test Clock Input)	Dedicated test logic clock used serially to shift test instruction, test data, and control inputs on the rising edge of the clock, and serially to shift the output data on the falling edge of the clock. The maximum clock frequency for TCK is 20 MHz.
TDI (Test Data Input)	Serial input for instruction and test data. Data is captured on the rising edge of the test logic clock.
TDO (Test Data Output)	Serial output for test instruction and data from the test logic. TDO is set to an Inactive Drive state (high impedance) when data scanning is not in progress.

Table 10 • Supported BST Public Instructions

Instruction	IR Code (IR2.IR0)	Instruction Type	Description
EXTEST	000	Mandatory	Allows the external circuitry and board-level interconnections to be tested by forcing a test pattern at the output pins and capturing test results at the input pins.
SAMPLE/PRELOAD	001	Mandatory	Allows a snapshot of the signals at the device pins to be captured and examined during operation
HIGH Z	101	Optional	Tristates all I/Os to allow external signals to drive pins. See the IEEE Standard 1149.1 specification.
CLAMP	110	Optional	Allows state of signals driven from component pins to be determined from the Boundary-Scan Register. See the IEEE Standard 1149.1 specification for details.
BYPASS	111	Mandatory	Enables the bypass register between the TDI and TDO pins. The test data passes through the selected device to adjacent devices in the test chain.

Figure 30 • 42MX SRAM Write Operation

Note: Identical timing for falling edge clock

Figure 31 • 42MX SRAM Synchronous Read Operation

Note: Identical timing for falling edge clock

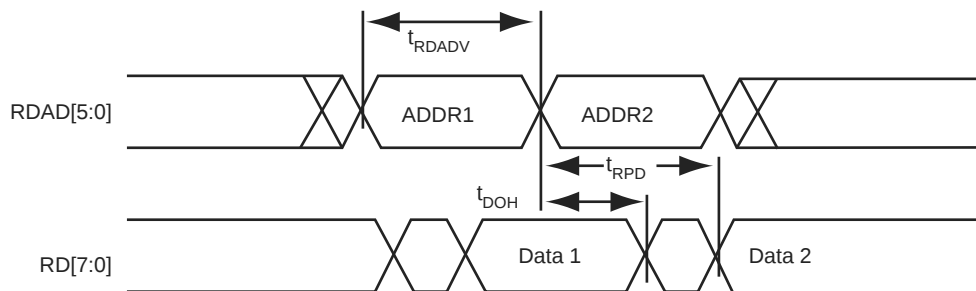
Figure 32 • 42MX SRAM Asynchronous Read Operation—Type 1 (Read Address Controlled)

Table 36 • A40MX04 Timing Characteristics (Nominal 5.0 V Operation) (continued)(Worst-Case Commercial Conditions, VCC = 4.75 V, T_J = 70°C)

Parameter / Description			–3 Speed		–2 Speed		–1 Speed		Std Speed		–F Speed		Units
			Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
t _{HENA}	Flip-Flop (Latch) Enable Hold		0.0		0.0		0.0		0.0		0.0		ns
t _{WCLKA}	Flip-Flop (Latch) Clock Active Pulse Width		3.3		3.8		4.3		5.0		7.0		ns
t _{WASYN}	Flip-Flop (Latch) Asynchronous Pulse Width		3.3		3.8		4.3		5.0		7.0		ns
t _A	Flip-Flop Clock Input Period		4.8		5.6		6.3		7.5		10.4		ns
f _{MAX}	Flip-Flop (Latch) Clock Frequency (FO = 128)			181		167		154		134		80	MHz
Input Module Propagation Delays													
t _{INyh}	Pad-to-Y HIGH			0.7		0.8		0.9		1.1		1.5	ns
t _{INyl}	Pad-to-Y LOW			0.6		0.7		0.8		1.0		1.3	ns
Input Module Predicted Routing Delays ¹													
t _{IRD1}	FO = 1 Routing Delay			2.1		2.4		2.2		3.2		4.5	ns
t _{IRD2}	FO = 2 Routing Delay			2.6		3.0		3.4		4.0		5.6	ns
t _{IRD3}	FO = 3 Routing Delay			3.1		3.6		4.1		4.8		6.7	ns
t _{IRD4}	FO = 4 Routing Delay			3.6		4.2		4.8		5.6		7.8	ns
t _{IRD8}	FO = 8 Routing Delay			5.7		6.6		7.5		8.8		12.4	ns
Global Clock Network													
t _{CKH}	Input Low to HIGH	FO = 16		4.6		5.3		6.0		7.0		9.8	ns
		FO = 128		4.6		5.3		6.0		7.0		9.8	
t _{CKL}	Input High to LOW	FO = 16		4.8		5.6		6.3		7.4		10.4	ns
		FO = 128		4.8		5.6		6.3		7.4		10.4	
t _{PWH}	Minimum Pulse Width HIGH	FO = 16	2.2		2.6		2.9		3.4		4.8		ns
		FO = 128	2.4		2.7		3.1		3.6		5.1		
t _{PWL}	Minimum Pulse Width LOW	FO = 16	2.2		2.6		2.9		3.4		4.8		ns
		FO = 128	2.4		2.7		3.01		3.6		5.1		
t _{CKSW}	Maximum Skew	FO = 16		0.4		0.5		0.5		0.6		0.8	ns
		FO = 128		0.5		0.6		0.7		0.8		1.2	
t _P	Minimum Period	FO = 16	4.7		5.4		6.1		7.2		10.0		ns
		FO = 128	4.8		5.6		6.3		7.5		10.4		
f _{MAX}	Maximum Frequency	FO = 16		188		175		160		139		83	MHz
		FO = 128		181		168		154		134		80	
TTL Output Module Timing ⁴													
t _{DLH}	Data-to-Pad HIGH			3.3		3.8		4.3		5.1		7.2	ns
t _{DHL}	Data-to-Pad LOW			4.0		4.6		5.2		6.1		8.6	ns
t _{ENZH}	Enable Pad Z to HIGH			3.7		4.3		4.9		5.8		8.0	ns
t _{ENZL}	Enable Pad Z to LOW			4.7		5.4		6.1		7.2		10.1	ns
t _{ENHZ}	Enable Pad HIGH to Z			7.9		9.1		10.4		12.2		17.1	ns

Table 38 • A42MX09 Timing Characteristics (Nominal 5.0 V Operation) (continued)(Worst-Case Commercial Conditions, VCCA = 4.75 V, T_J = 70°C)

Parameter / Description			–3 Speed		–2 Speed		–1 Speed		Std Speed		–F Speed		Units
			Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
Input Module Propagation Delays													
t _{INYH}	Pad-to-Y HIGH			1.0		1.2		1.3		1.6		2.2	ns
t _{INYL}	Pad-to-Y LOW			0.8		0.9		1.0		1.2		1.7	ns
t _{INGH}	G to Y HIGH			1.3		1.4		1.6		1.9		2.7	ns
t _{INGL}	G to Y LOW			1.3		1.4		1.6		1.9		2.7	ns
Input Module Predicted Routing Delays ²													
t _{IRD1}	FO = 1 Routing Delay			2.0		2.2		2.5		3.0		4.2	ns
t _{IRD2}	FO = 2 Routing Delay			2.3		2.5		2.9		3.4		4.7	ns
t _{IRD3}	FO = 3 Routing Delay			2.5		2.8		3.2		3.7		5.2	ns
t _{IRD4}	FO = 4 Routing Delay			2.8		3.1		3.5		4.1		5.7	ns
t _{IRD8}	FO = 8 Routing Delay			3.7		4.1		4.7		5.5		7.7	ns
Global Clock Network													
t _{CKH}	Input LOW to HIGH	FO = 32		2.4		2.7		3.0		3.6		5.0	ns
		FO = 256		2.7		3.0		3.4		4.0		5.5	ns
t _{CKL}	Input HIGH to LOW	FO = 32		3.5		3.9		4.4		5.2		7.3	ns
		FO = 256		3.9		4.3		4.9		5.7		8.0	ns
t _{PWH}	Minimum Pulse Width HIGH	FO = 32	1.2		1.4		1.5		1.8		2.5		ns
		FO = 256	1.3		1.5		1.7		2.0		2.7		ns
t _{PWL}	Minimum Pulse Width LOW	FO = 32	1.2		1.4		1.5		1.8		2.5		ns
		FO = 256	1.3		1.5		1.7		2.0		2.7		ns
t _{CKSW}	Maximum Skew	FO = 32		0.3		0.3		0.4		0.5		0.6	ns
		FO = 256		0.3		0.3		0.4		0.5		0.6	ns
t _{SUEXT}	Input Latch External Set-Up	FO = 32	0.0		0.0		0.0		0.0		0.0		ns
		FO = 256	0.0		0.0		0.0		0.0		0.0		ns
t _{HEXT}	Input Latch External Hold	FO = 32	2.3		2.6		3.0		3.5		4.9		ns
		FO = 256	2.2		2.4		3.3		3.9		5.5		ns
t _P	Minimum Period	FO = 32	3.4		3.7		4.0		4.7		7.8		ns
		FO = 256	3.7		4.1		4.5		5.2		8.6		ns
f _{MAX}	Maximum Frequency	FO = 32		296		269		247		215		129	MHz
		FO = 256		268		244		224		195		117	MHz

Table 39 • A42MX09 Timing Characteristics (Nominal 3.3 V Operation) (continued)(Worst-Case Commercial Conditions, VCCA = 3.0 V, T_J = 70°C)

Parameter / Description		–3 Speed		–2 Speed		–1 Speed		Std Speed		–F Speed		Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
TTL Output Module Timing ⁵												
t _{DLH}	Data-to-Pad HIGH		3.4		3.8		4.3		5.1		7.1	ns
t _{DHL}	Data-to-Pad LOW		4.0		4.5		5.1		6.1		8.3	ns
t _{ENZH}	Enable Pad Z to HIGH		3.7		4.1		4.6		5.5		7.6	ns
t _{ENZL}	Enable Pad Z to LOW		4.1		4.5		5.1		6.1		8.5	ns
t _{ENHZ}	Enable Pad HIGH to Z		6.9		7.6		8.6		10.2		14.2	ns
t _{ENLZ}	Enable Pad LOW to Z		7.5		8.3		9.4		11.1		15.5	ns
t _{GLH}	G-to-Pad HIGH		5.8		6.5		7.3		8.6		12.0	ns
t _{GHL}	G-to-Pad LOW		5.8		6.5		7.3		8.6		12.0	ns
t _{LSU}	I/O Latch Set-Up	0.7		0.8		0.9		1.0		1.4		ns
t _{LH}	I/O Latch Hold	0.0		0.0		0.0		0.0		0.0		ns
t _{LCO}	I/O Latch Clock-to-Out (Pad-to-Pad), 64 Clock Loading		8.7		9.7		10.9		12.9		18.0	ns
t _{ACO}	Array Clock-to-Out (Pad-to-Pad), 64 Clock Loading		12.2		13.5		15.4		18.1		25.3	ns
d _{TLH}	Capacity Loading, LOW to HIGH		0.00		0.00		0.00		0.10		0.01	ns/pF
d _{THL}	Capacity Loading, HIGH to LOW		0.09		0.10		0.10		0.10		0.10	ns/pF

Table 44 • A42MX36 Timing Characteristics (Nominal 5.0 V Operation)(Worst-Case Commercial Conditions, VCCA = 4.75 V, T_J = 70°C)

Parameter / Description		-3 Speed		-2 Speed		-1 Speed		Std Speed		-F Speed		Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
CMOS Output Module Timing ⁵												
t _{DLH}	Data-to-Pad HIGH		3.5		3.9		4.5		5.2		7.3	ns
t _{DHL}	Data-to-Pad LOW		2.5		2.7		3.1		3.6		5.1	ns
t _{ENZH}	Enable Pad Z to HIGH		2.7		3.0		3.3		3.9		5.5	ns
t _{ENZL}	Enable Pad Z to LOW		2.9		3.3		3.7		4.3		6.1	ns
t _{ENHZ}	Enable Pad HIGH to Z		5.3		5.8		6.6		7.8		10.9	ns
t _{ENLZ}	Enable Pad LOW to Z		4.9		5.5		6.2		7.3		10.2	ns
t _{GLH}	G-to-Pad HIGH		5.0		5.6		6.3		7.5		10.4	ns
t _{GHL}	G-to-Pad LOW		5.0		5.6		6.3		7.5		10.4	ns
t _{LSU}	I/O Latch Set-Up	0.5		0.5		0.6		0.7		1.0		ns
t _{LH}	I/O Latch Hold	0.0		0.0		0.0		0.0		0.0		ns
t _{LCO}	I/O Latch Clock-to-Out (Pad-to-Pad) 32 I/O		5.7		6.3		7.1		8.4		11.8	ns
t _{ACO}	Array Latch Clock-to-Out (Pad-to-Pad) 32 I/O		7.8		8.6		9.8		11.5		16.1	ns
d _{TLH}	Capacitive Loading, LOW to HIGH		0.07		0.08		0.09		0.10		0.14	ns/pF
d _{THL}	Capacitive Loading, HIGH to LOW		0.07		0.08		0.09		0.10		0.14	ns/pF

1. For dual-module macros, use t_{PD1} + t_{RD1} + t_{PDn}, t_{CO} + t_{RD1} + t_{PDn}, or t_{PD1} + t_{RD1} + t_{SUD}, whichever is appropriate.
2. Routing delays are for typical designs across worst-case operating conditions. These parameters should be used for estimating device performance. Post-route timing analysis or simulation is required to determine actual performance.
3. Data applies to macros based on the S-module. Timing parameters for sequential macros constructed from C-modules can be obtained from the Timer utility.
4. Set-up and hold timing parameters for the Input Buffer Latch are defined with respect to the PAD and the D input. External setup/hold timing parameters must account for delay from an external PAD signal to the G inputs. Delay from an external PAD signal to the G input subtracts (adds) to the internal setup (hold) time.
5. Delays based on 35 pF loading.

Table 45 • A42MX36 Timing Characteristics (Nominal 3.3 V Operation) (Worst-Case Commercial Conditions, VCCA = 3.0 V, T_J = 70°C)

Parameter / Description		-3 Speed		-2 Speed		-1 Speed		Std Speed		-F Speed		Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
Logic Module Combinatorial Functions ¹												
t _{PD}	Internal Array Module Delay		1.9		2.1		2.3		2.7		3.8	ns
t _{PDD}	Internal Decode Module Delay		2.2		2.5		2.8		3.3		4.7	ns
Logic Module Predicted Routing Delays ²												
t _{RD1}	FO = 1 Routing Delay		1.3		1.5		1.7		2.0		2.7	ns
t _{RD2}	FO = 2 Routing Delay		1.8		2.0		2.3		2.7		3.7	ns
t _{RD3}	FO = 3 Routing Delay		2.3		2.5		2.8		3.4		4.7	ns
t _{RD4}	FO = 4 Routing Delay		2.8		3.1		3.5		4.1		5.7	ns

Table 45 • A42MX36 Timing Characteristics (Nominal 3.3 V Operation) (continued)(Worst-Case Commercial Conditions, VCCA = 3.0 V, T_J = 70°C)

Parameter / Description			–3 Speed		–2 Speed		–1 Speed		Std Speed		–F Speed		Units
			Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
Input Module Predicted Routing Delays ²													
t _{IRD1}	FO = 1 Routing Delay		2.8		3.1		3.5		4.1		5.7		ns
t _{IRD2}	FO = 2 Routing Delay		3.2		3.5		4.1		4.8		6.7		ns
t _{IRD3}	FO = 3 Routing Delay		3.7		4.1		4.7		5.5		7.7		ns
t _{IRD4}	FO = 4 Routing Delay		4.2		4.6		5.3		6.2		8.7		ns
t _{IRD8}	FO = 8 Routing Delay		6.1		6.8		7.7		9.0		12.6		ns
Global Clock Network													
t _{CKH}	Input LOW to HIGH	FO = 32	4.6		5.1		5.7		6.7		9.3		ns
		FO = 635	5.0		5.6		6.3		7.4		10.3		ns
t _{CKL}	Input HIGH to LOW	FO = 32	5.3		5.9		6.7		7.8		11.0		ns
		FO = 635	6.8		7.6		8.6		10.1		14.1		ns
t _{PWH}	Minimum Pulse Width HIGH	FO = 32	2.5		2.7		3.1		3.6		5.1		ns
		FO = 635	2.8		3.1		3.5		4.1		5.7		ns
t _{PWL}	Minimum Pulse Width LOW	FO = 32	2.5		2.7		3.1		3.6		5.1		ns
		FO = 635	2.8		3.1		3.5		4.1		5.7		ns
t _{CKSW}	Maximum Skew	FO = 32	1.0		1.2		1.3		1.5		2.2		ns
		FO = 635	1.0		1.2		1.3		1.5		2.2		ns
t _{SUEXT}	Input Latch External Set-Up	FO = 32	0.0		0.0		0.0		0.0		0.0		ns
		FO = 635	0.0		0.0		0.0		0.0		0.0		ns
t _{HEXT}	Input Latch External Hold	FO = 32	4.0		4.4		5.0		5.9		8.2		ns
		FO = 635	4.6		5.2		5.9		6.9		9.6		ns
t _P	Minimum Period (1/f _{MAX})	FO = 32	9.2		10.2		11.1		12.7		21.2		ns
		FO = 635	9.9		11.0		12.0		13.8		23.0		ns
f _{MAX}	Maximum Datapath Frequency	FO = 32	108		98		90		79		47		MHz
		FO = 635	100		91		83		73		44		MHz
TTL Output Module Timing ⁵													
t _{DLH}	Data-to-Pad HIGH		3.6		4.0		4.5		5.3		7.4		ns
t _{DHL}	Data-to-Pad LOW		4.2		4.6		5.2		6.2		8.6		ns
t _{ENZH}	Enable Pad Z to HIGH		3.7		4.2		4.7		5.5		7.7		ns
t _{ENZL}	Enable Pad Z to LOW		4.1		4.6		5.2		6.1		8.5		ns
t _{ENHZ}	Enable Pad HIGH to Z		7.34		8.2		9.3		10.9		15.3		ns
TTL Output Module Timing ⁵													
t _{ENLZ}	Enable Pad LOW to Z		6.9		7.6		8.7		10.2		14.3		ns
t _{GLH}	G-to-Pad HIGH		4.9		5.5		6.2		7.3		10.2		ns
t _{GHL}	G-to-Pad LOW		4.9		5.5		6.2		7.3		10.2		ns
t _{LSU}	I/O Latch Output Set-Up		0.7		0.7		0.8		1.0		1.4		ns
t _{LH}	I/O Latch Output Hold		0.0		0.0		0.0		0.0		0.0		ns
t _{LCO}	I/O Latch Clock-to-Out (Pad-to-Pad) 32 I/O		7.9		8.8		10.0		11.8		16.5		ns

Table 52 • PQ160

PQ160			
Pin Number	A42MX09 Function	A42MX16 Function	A42MX24 Function
132	I/O	I/O	I/O
133	I/O	I/O	I/O
134	I/O	I/O	I/O
135	NC	VCCA	VCCA
136	I/O	I/O	I/O
137	I/O	I/O	I/O
138	NC	VCCA	VCCA
139	VCCI	VCCI	VCCI
140	GND	GND	GND
141	NC	I/O	I/O
142	I/O	I/O	I/O
143	I/O	I/O	I/O
144	I/O	I/O	I/O
145	GND	GND	GND
146	NC	I/O	I/O
147	I/O	I/O	I/O
148	I/O	I/O	I/O
149	I/O	I/O	I/O
150	NC	VCCA	VCCA
151	NC	I/O	I/O
152	NC	I/O	I/O
153	NC	I/O	I/O
154	NC	I/O	I/O
155	GND	GND	GND
156	I/O	I/O	I/O
157	I/O	I/O	I/O
158	I/O	I/O	I/O
159	MODE	MODE	MODE
160	GND	GND	GND

Table 53 • PQ208

PQ208			
Pin Number	A42MX16 Function	A42MX24 Function	A42MX36 Function
132	VCCI	VCCI	VCCI
133	VCCA	VCCA	VCCA
134	I/O	I/O	I/O
135	I/O	I/O	I/O
136	VCCA	VCCA	VCCA
137	I/O	I/O	I/O
138	I/O	I/O	I/O
139	I/O	I/O	I/O
140	I/O	I/O	I/O
141	NC	I/O	I/O
142	I/O	I/O	I/O
143	I/O	I/O	I/O
144	I/O	I/O	I/O
145	I/O	I/O	I/O
146	NC	I/O	I/O
147	NC	I/O	I/O
148	NC	I/O	I/O
149	NC	I/O	I/O
150	GND	GND	GND
151	I/O	I/O	I/O
152	I/O	I/O	I/O
153	I/O	I/O	I/O
154	I/O	I/O	I/O
155	I/O	I/O	I/O
156	I/O	I/O	I/O
157	GND	GND	GND
158	I/O	I/O	I/O
159	SDI, I/O	SDI, I/O	SDI, I/O
160	I/O	I/O	I/O
161	I/O	WD, I/O	WD, I/O
162	I/O	WD, I/O	WD, I/O
163	I/O	I/O	I/O
164	VCCI	VCCI	VCCI
165	NC	I/O	I/O
166	NC	I/O	I/O
167	I/O	I/O	I/O
168	I/O	WD, I/O	WD, I/O

Table 54 • PQ240

PQ240	
Pin Number	A42MX36 Function
15	QCLKC, I/O
16	I/O
17	WD, I/O
18	WD, I/O
19	I/O
20	I/O
21	WD, I/O
22	WD, I/O
23	I/O
24	PRB, I/O
25	I/O
26	CLKB, I/O
27	I/O
28	GND
29	VCCA
30	VCCI
31	I/O
32	CLKA, I/O
33	I/O
34	PRA, I/O
35	I/O
36	I/O
37	WD, I/O
38	WD, I/O
39	I/O
40	I/O
41	I/O
42	I/O
43	I/O
44	I/O
45	QCLKD, I/O
46	I/O
47	WD, I/O
48	WD, I/O
49	I/O
50	I/O
51	I/O

Figure 47 • VQ100

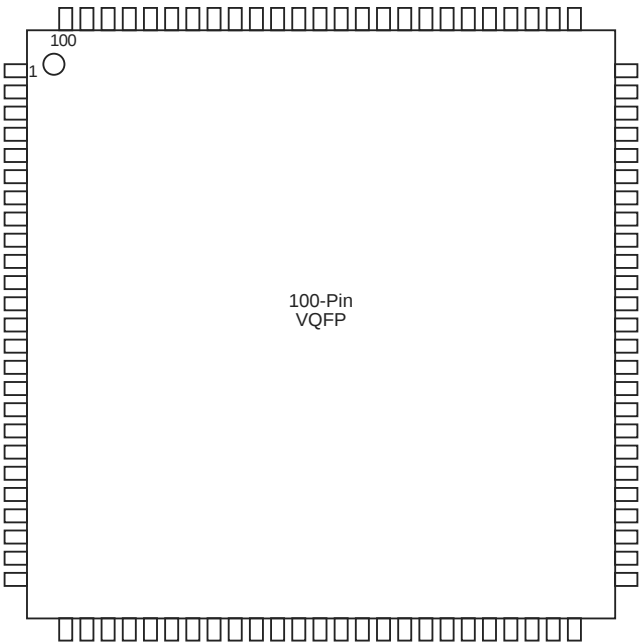


Table 56 • VQ100

VQ100		
Pin Number	A42MX09 Function	A42MX16 Function
1	I/O	I/O
2	MODE	MODE
3	I/O	I/O
4	I/O	I/O
5	I/O	I/O
6	I/O	I/O
7	GND	GND
8	I/O	I/O
9	I/O	I/O
10	I/O	I/O
11	I/O	I/O
12	I/O	I/O
13	I/O	I/O
14	VCCA	NC
15	VCCI	VCCI
16	I/O	I/O
17	I/O	I/O
18	I/O	I/O
19	I/O	I/O
20	GND	GND

Table 56 • VQ100

VQ100		
Pin Number	A42MX09 Function	A42MX16 Function
57	I/O	I/O
58	I/O	I/O
59	I/O	I/O
60	I/O	I/O
61	I/O	I/O
62	LP	LP
63	VCCA	VCCA
64	VCCI	VCCI
65	VCCA	VCCA
66	I/O	I/O
67	I/O	I/O
68	I/O	I/O
69	I/O	I/O
70	GND	GND
71	I/O	I/O
72	I/O	I/O
73	I/O	I/O
74	I/O	I/O
75	I/O	I/O
76	I/O	I/O
77	SDI, I/O	SDI, I/O
78	I/O	I/O
79	I/O	I/O
80	I/O	I/O
81	I/O	I/O
82	GND	GND
83	I/O	I/O
84	I/O	I/O
85	PRA, I/O	PRA, I/O
86	I/O	I/O
87	CLKA, I/O	CLKA, I/O
88	VCCA	VCCA
89	I/O	I/O
90	CLKB, I/O	CLKB, I/O
91	I/O	I/O
92	PRB, I/O	PRB, I/O

Table 56 • VQ100

VQ100		
Pin Number	A42MX09 Function	A42MX16 Function
93	I/O	I/O
94	GND	GND
95	I/O	I/O
96	I/O	I/O
97	I/O	I/O
98	I/O	I/O
99	I/O	I/O
100	DCLK, I/O	DCLK, I/O

Figure 48 • TQ176

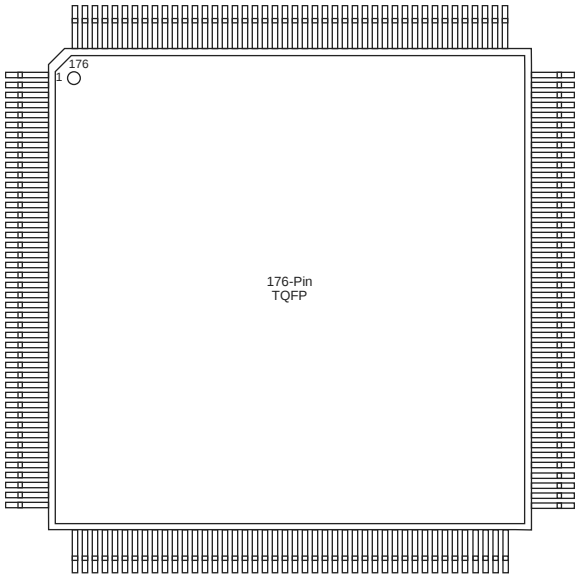


Table 57 • TQ176

TQ176			
Pin Number	A42MX09 Function	A42MX16 Function	A42MX24 Function
1	GND	GND	GND
2	MODE	MODE	MODE
3	I/O	I/O	I/O
4	I/O	I/O	I/O
5	I/O	I/O	I/O
6	I/O	I/O	I/O
7	I/O	I/O	I/O
8	NC	NC	I/O
9	I/O	I/O	I/O

Figure 50 • CQ256

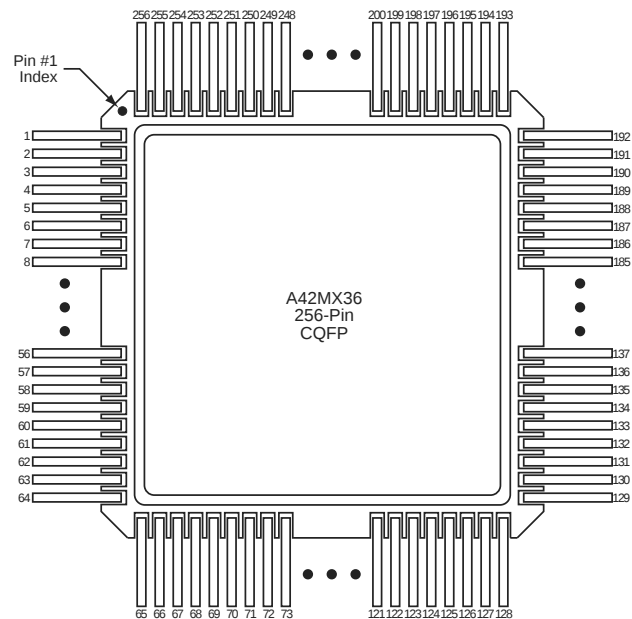


Table 59 • CQ256

CQ256	
Pin Number	A42MX36 Function
1	NC
2	GND
3	I/O
4	I/O
5	I/O
6	I/O
7	I/O
8	I/O
9	I/O
10	GND
11	I/O
12	I/O
13	I/O
14	I/O
15	I/O
16	I/O
17	I/O
18	I/O
19	I/O
20	I/O
21	I/O

Table 59 • CQ256

CQ256	
Pin Number	A42MX36 Function
96	VCCA
97	GND
98	GND
99	I/O
100	I/O
101	I/O
102	I/O
103	I/O
104	I/O
105	WD, I/O
106	WD, I/O
107	I/O
108	I/O
109	WD, I/O
110	WD, I/O
111	I/O
112	QCLKA, I/O
113	I/O
114	GND
115	I/O
116	I/O
117	I/O
118	I/O
119	VCCI
120	I/O
121	WD, I/O
122	WD, I/O
123	I/O
124	I/O
125	I/O
126	I/O
127	GND
128	NC
129	NC
130	NC
131	GND
132	I/O